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IBM Docket No. FIS920030024US1

Date of Deposit: September 18, 2003

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In the United States Patent and Trademark Office

Date: September 18, 2003

In re Application William Wille et al.

Filed: June 24, 2003

of:

For: METHOD FOR FORMING DAMASCENE STRUCTURE

UTILIZING PLANARIZING MATERIAL COUPLED WITH

DIFFUSION BARRIER MATERIAL

Serial Number:

10/604,056

Art Unit:

Examiner:

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

Hon. Commissioner of Patents and Trademarks Alexandria, VA 22313-1450

Sir:

Pursuant to the duty of disclosure set forth in 37 C.F.R. § 1.56, and further pursuant to the provisions of 37 C.F.R. §§ 1.97 and 1.98, Applicants hereby respectfully submit copies of the prior publications as listed on Form PTO-1449, attached hereto. Applicants also hereby submit a copy of the following pending U.S. patent application:

IBM Dock t No. FIS920030024US1

Ser. No.: 09/256, 034

Filing Date: February 23, 1999 Attorney Docket No.: YO998-056 Inventors: M. Angelopoulos et al.

Title: Multilayered Resist System Using Tuned Polymer Films as Underlayers

and Methods of Fabrication Thereof

In citing these documents, no representation is made nor intended as to the pertinency or non-pertinency of the art, that better art than listed is not available, or that other art is not applicable.

Pursuant to 37 C.F.R. §§ 1.97(b), no fee is believed to be due for this submission. If any fees are required, however, the Commissioner is hereby authorized to charge such fees to Deposit Account No. 09-0458.

Respectfully Submitted,

Margaret A. Pepper

Attorney for Applicant

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TION DISCLOSURE CITATION	Applicant(s)	10/604,056
Use several sheets if necessary)	William Wille, et al.	
	Filing Date 6/24/03	Group Art Unit
OTHER DOCUMENTS (Including Author, Tit	le, Date, Pertinent Pages, Etc.)	
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	DATE CONSIDERED	
	OTHER DOCUMENTS (Including Author, Tit. "A High Performance 0.13 um C pper BEOL TeleEE 2000 International Interconnect Technics of International Inter	William Wille, et al. Piling Date 6/24/03 OTHER DOCUMENTS (Including Author, Title, Date, Perinent Pages, Etc.) "A High Performance 0.13 um C pper BEOL Techn logy with Low-K Dielectric" R.I. IEEE 2000 International Interconnect Technology Conference, 5-7 June, 2000, p "A Manufacturable Copper/Low-k SIOC/SICN Process Technology for 90nm-node HI High Resolution 248 nm Bilayer Resist" Qinghuang Lin, et al., Proc. SPIE - Int. Spp. 241-50. "Surface treatment validation of inorganic BARC on 0.25 um Non Volatile Memory to Microelectronic Engineering 46 (1999), pp. 47-50. "Effects of Crosslinking Agent on Lithographic Performance of Negative-Tone Resist Qinghuang Lin, et al. Proc. SPIE - Int. Soc. Opt. Eng. (USA), vol 3049, pp. 974-87. Patent Application, Serial Number 09/256,034, dated 2/23/99, Inventor Entitled Multilayered Resist System Using Tuned Polymer Films as Under Fabrication Thereof.